

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/614,132	SOMAYAJI ET AL.	
Examiner		Art Unit		Page 1 of 1
Leigh Marie Garbowski		2825		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,598,208	07-2003	Sasaki et al.	716/4
	B	US-6,742,167	05-2004	Grau, Gunter	716/4
	C	US-2004/0194043	09-2004	Sundar et al.	716/005
	D	US-6,766,498	07-2004	Sharma et al.	716/5
	E	US-6,826,517	11-2004	Okada, Takako	703/2
	F	US-6,775,807	08-2004	Lowther et al.	716/1
	G	US-6,513,001	01-2003	Kapur et al.	703/13
	H	US-6,397,171	05-2002	Belk, Nathan R.	703/14
	I	US-5,812,434	09-1998	Nagase et al.	703/2
	J	US-5,629,621	05-1997	Goldfine et al.	324/239
	K	US-6,857,113	02-2005	Gentry et al.	716/5
	L	US-6,038,383	03-2000	Young et al.	716/5
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagaraj et al., "A Practical Approach to Static Signal Electromigration Analysis," 1998 ACM/DAC, pages 572-577.
	V	Donohoe et al., "Simple Edge Basis Functions for Open-Ended Bodies of Revolution," 1995 IEEE, pages 329-332.
	W	Ting et al., "AC Electromigration Characterization and Modeling of Multilayered Interconnects," 1993 IEEE/IRPS, pages 311-316.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.